# NVD5C454N

# MOSFET – Power, Single N-Channel
## 40 V, 4.2 mΩ, 83 A

**Features**

- Low $R_{DS(on)}$ to Minimize Conduction Losses
- Low $Q_G$ and Capacitance to Minimize Driver Losses
- AEC−Q101 Qualified and PPAP Capable
- These Devices are Pb−Free, Halogen Free/BFR Free and are RoHS Compliant

**MAXIMUM RATINGS** ($T_J$ = 25°C unless otherwise noted)

| Parameter | | | Symbol | Value | Unit |
|---|---|---|---|---|---|
| Drain−to−Source Voltage | | | $V_{DSS}$ | 40 | V |
| Gate−to−Source Voltage | | | $V_{GS}$ | ±20 | V |
| Continuous Drain Current $R_{\theta JC}$ (Notes 1 & 3) | Steady State | $T_C$ = 25°C | $I_D$ | 82 | A |
| | | $T_C$ = 100°C | | 58 | |
| Power Dissipation $R_{\theta JC}$ (Note 1) | | $T_C$ = 25°C | $P_D$ | 56 | W |
| | | $T_C$ = 100°C | | 28 | |
| Continuous Drain Current $R_{\theta JA}$ (Notes 1, 2 & 3) | Steady State | $T_A$ = 25°C | $I_D$ | 19 | A |
| | | $T_A$ = 100°C | | 14 | |
| Power Dissipation $R_{\theta JA}$ (Notes 1 & 2) | | $T_A$ = 25°C | $P_D$ | 3.1 | W |
| | | $T_A$ = 100°C | | 1.5 | |
| Pulsed Drain Current | $T_A$ = 25°C, $t_p$ = 10 μs | | $I_{DM}$ | 446 | A |
| Operating Junction and Storage Temperature | | | $T_J$, $T_{stg}$ | −55 to 175 | °C |
| Source Current (Body Diode) | | | $I_S$ | 46 | A |
| Single Pulse Drain−to−Source Avalanche Energy ($T_J$ = 25°C, $I_{L(pk)}$ = 8.3 A) | | | $E_{AS}$ | 205 | mJ |
| Lead Temperature for Soldering Purposes (1/8″ from case for 10 s) | | | $T_L$ | 260 | °C |

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

**THERMAL RESISTANCE MAXIMUM RATINGS**

| Parameter | Symbol | Value | Unit |
|---|---|---|---|
| Junction−to−Case (Drain) (Note 1) | $R_{\theta JC}$ | 2.7 | °C/W |
| Junction−to−Ambient − Steady State (Note 2) | $R_{\theta JA}$ | 48.4 | |

1. The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
2. Surface−mounted on FR4 board using a 650 $mm^2$, 2 oz. Cu pad.
3. Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.

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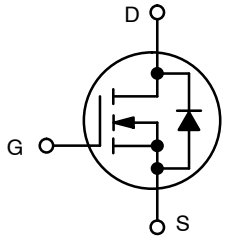
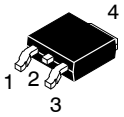
| $V_{(BR)DSS}$ | $R_{DS(on)}$ | $I_D$ |
|---|---|---|
| 40 V | 4.2 mΩ @ 10 V | 83 A |

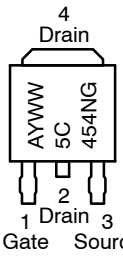



**N−CHANNEL MOSFET**




**DPAK**
**CASE 369C**
**STYLE 2**

**MARKING DIAGRAM & PIN ASSIGNMENT**




A = Assembly Location
Y = Year
WW = Work Week
5C454N = Device Code
G = Pb−Free Package

**ORDERING INFORMATION**

See detailed ordering and shipping information on page 5 of this data sheet.

**ELECTRICAL CHARACTERISTICS** ($T_J$ = 25°C unless otherwise noted)

| Parameter | Symbol | Test Condition | | Min | Typ | Max | Unit |
|---|---|---|---|---|---|---|---|
| **OFF CHARACTERISTICS** | | | | | | | |
| Drain−to−Source Breakdown Voltage | $V_{(BR)DSS}$ | $V_{GS}$ = 0 V, $I_D$ = 250 μA | | 40 | | | V |
| Drain−to−Source Breakdown Voltage Temperature Coefficient | $V_{(BR)DSS}/T_J$ | | | | 15 | | mV/°C |
| Zero Gate Voltage Drain Current | $I_{DSS}$ | $V_{GS}$ = 0 V, $V_{DS}$ = 40 V | $T_J$ = 25°C | | | 10 | μA |
| | | | $T_J$ = 125°C | | | 250 | |
| Gate−to−Source Leakage Current | $I_{GSS}$ | $V_{DS}$ = 0 V, $V_{GS}$ = 20 V | | | | 100 | nA |
| **ON CHARACTERISTICS** (Note 4) | | | | | | | |
| Gate Threshold Voltage | $V_{GS(TH)}$ | $V_{GS}$ = $V_{DS}$, $I_D$ = 70 μA | | 2.0 | | 4.0 | V |
| Negative Threshold Temperature Coefficient | $V_{GS(TH)}/T_J$ | | | | 6.9 | | mV/°C |
| Drain−to−Source On Resistance | $R_{DS(on)}$ | $V_{GS}$ = 10 V, $I_D$ = 40 A | | | 3.6 | 4.2 | mΩ |
| Forward Transconductance | $g_{FS}$ | $V_{DS}$ = 3 V, $I_D$ = 40 A | | | 80 | | S |
| **CHARGES, CAPACITANCES AND GATE RESISTANCES** | | | | | | | |
| Input Capacitance | $C_{iss}$ | $V_{GS}$ = 0 V, f = 1.0 MHz, $V_{DS}$ = 25 V | | | 1900 | | pF |
| Output Capacitance | $C_{oss}$ | | | | 950 | | |
| Reverse Transfer Capacitance | $C_{rss}$ | | | | 48 | | |
| Total Gate Charge | $Q_{G(TOT)}$ | $V_{GS}$ = 10 V, $V_{DS}$ = 32 V, $I_D$ = 40 A | | | 32 | | nC |
| Threshold Gate Charge | $Q_{G(TH)}$ | | | | 5.7 | | |
| Gate−to−Source Charge | $Q_{GS}$ | | | | 9.5 | | |
| Gate−to−Drain Charge | $Q_{GD}$ | | | | 6.6 | | |
| Plateau Voltage | $V_{GP}$ | | | | 4.8 | | V |
| **SWITCHING CHARACTERISTICS** (Note 5) | | | | | | | |
| Turn−On Delay Time | $t_{d(on)}$ | $V_{GS}$ = 10 V, $V_{DS}$ = 32 V, $I_D$ = 40 A, $R_G$ = 2.5 Ω | | | 11 | | ns |
| Rise Time | $t_r$ | | | | 47 | | |
| Turn−Off Delay Time | $t_{d(off)}$ | | | | 24 | | |
| Fall Time | $t_f$ | | | | 8 | | |
| **DRAIN−SOURCE DIODE CHARACTERISTICS** | | | | | | | |
| Forward Diode Voltage | $V_{SD}$ | $V_{GS}$ = 0 V, $I_S$ = 40 A | $T_J$ = 25°C | | 0.9 | 1.2 | V |
| | | | $T_J$ = 125°C | | 0.8 | | |
| Reverse Recovery Time | $t_{RR}$ | $V_{GS}$ = 0 V, dIs/dt = 100 A/μs, $I_S$ = 40 A | | | 45 | | ns |
| Charge Time | ta | | | | 24 | | |
| Discharge Time | tb | | | | 21 | | |
| Reverse Recovery Charge | $Q_{RR}$ | | | | 20 | | nC |

4. Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2%.
5. Switching characteristics are independent of operating junction temperatures.

## TYPICAL CHARACTERISTICS

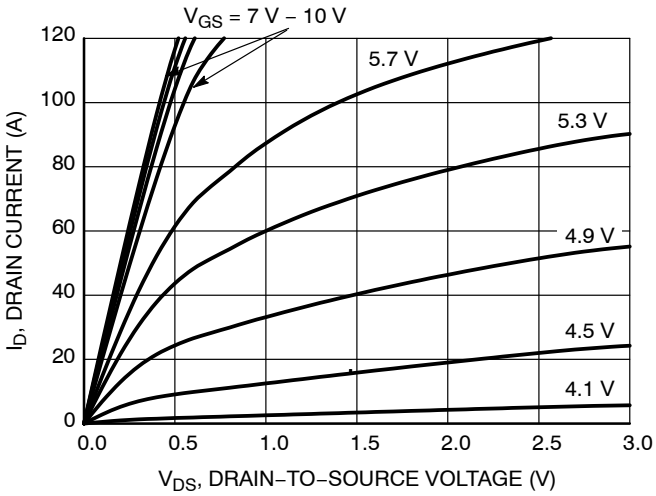



**Figure 1. On–Region Characteristics**

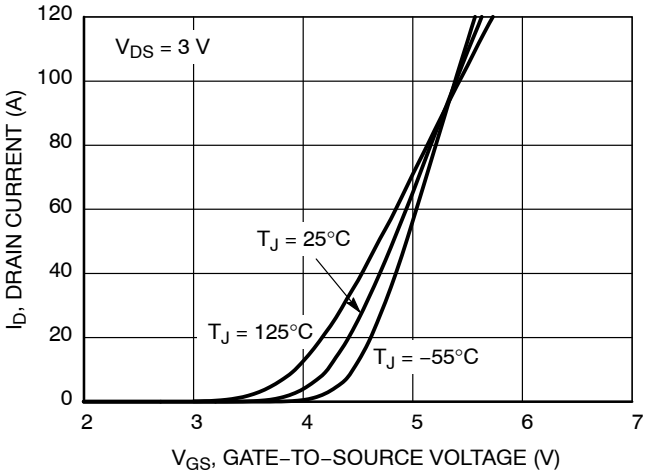



**Figure 2. Transfer Characteristics**

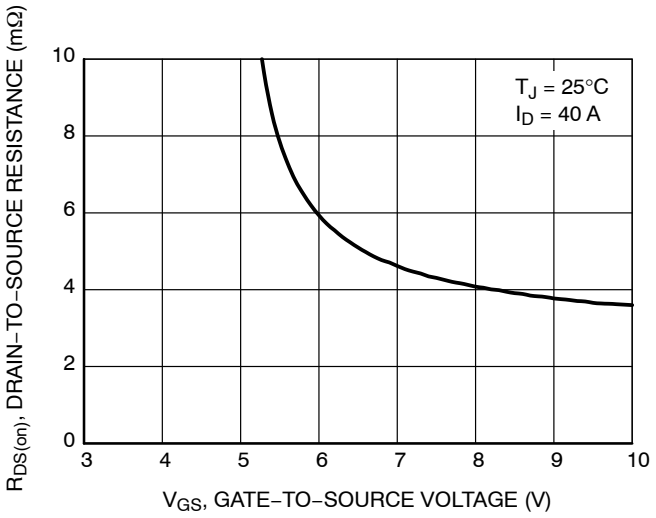



**Figure 3. On–Resistance vs. Gate–to–Source Voltage**

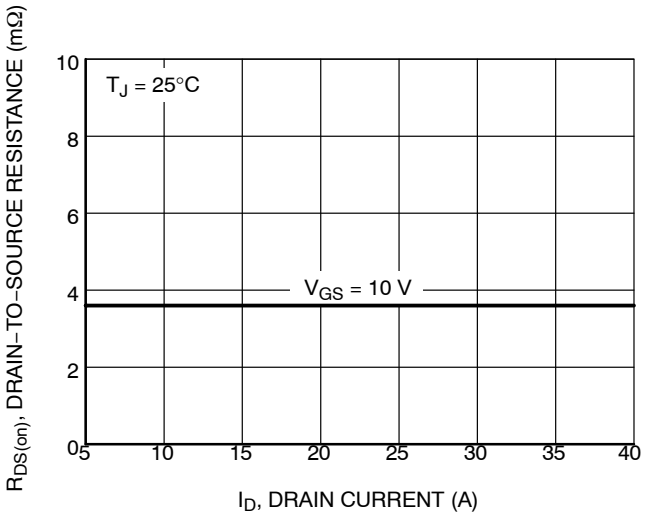



**Figure 4. On–Resistance vs. Drain Current and Gate Voltage**

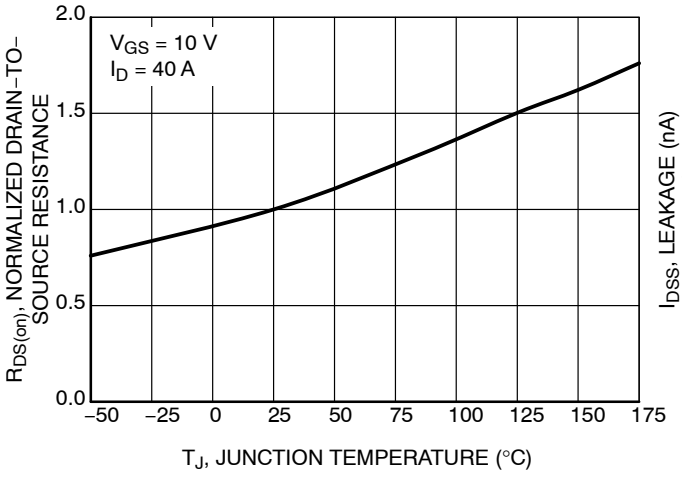



**Figure 5. On–Resistance Variation with Temperature**

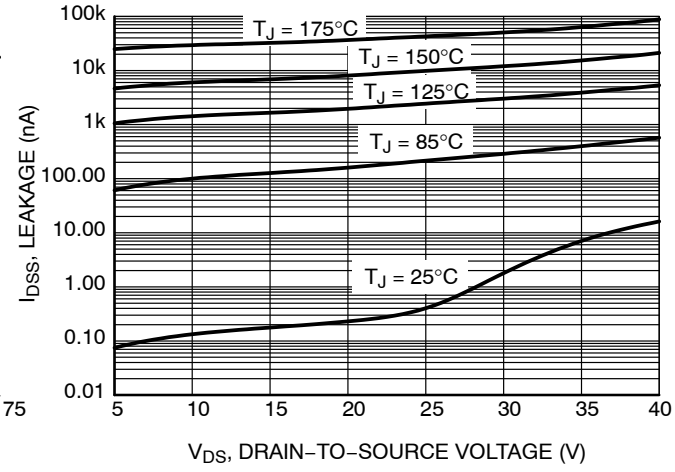



**Figure 6. Drain–to–Source Leakage Current vs. Voltage**

## TYPICAL CHARACTERISTICS

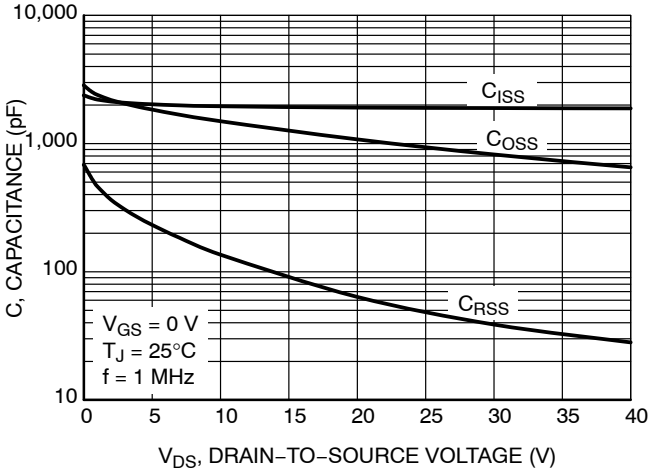



**Figure 7. Capacitance Variation**

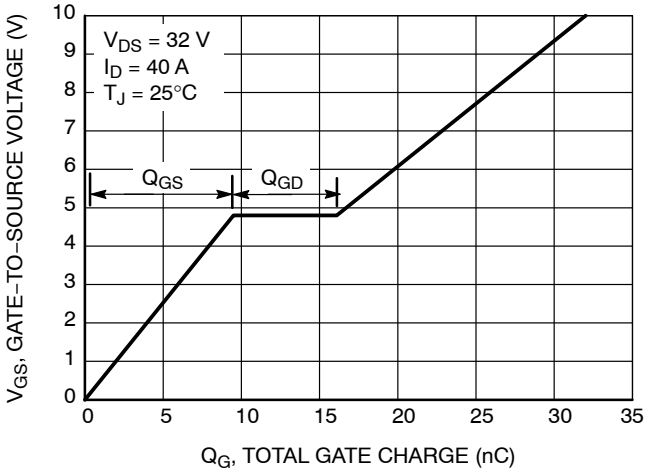



**Figure 8. Gate−to−Source vs. Total Charge**

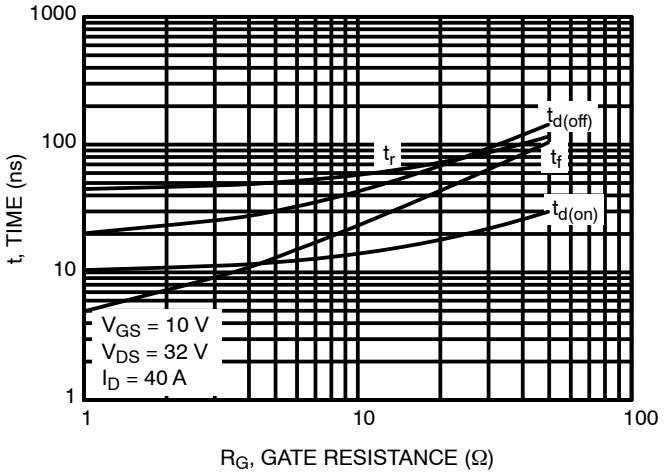



**Figure 9. Resistive Switching Time Variation vs. Gate Resistance**

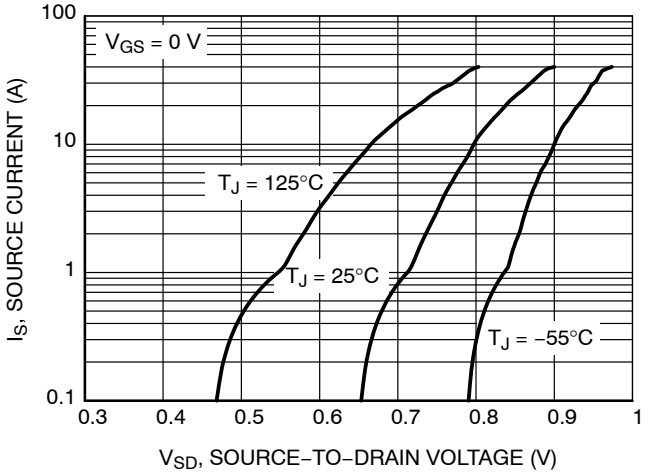



**Figure 10. Diode Forward Voltage vs. Current**

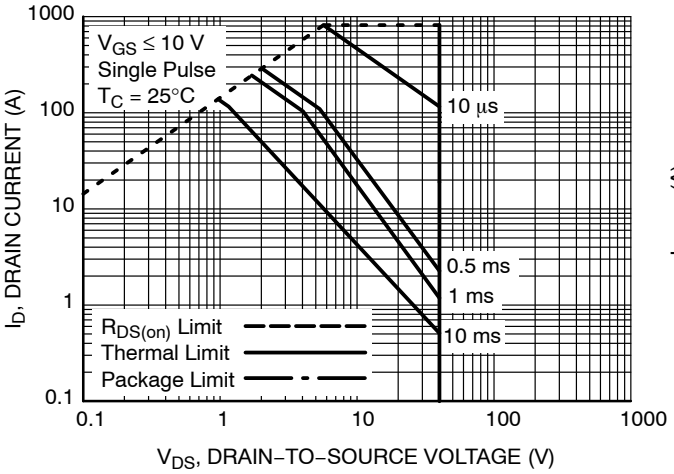



**Figure 11. Maximum Rated Forward Biased Safe Operating Area**

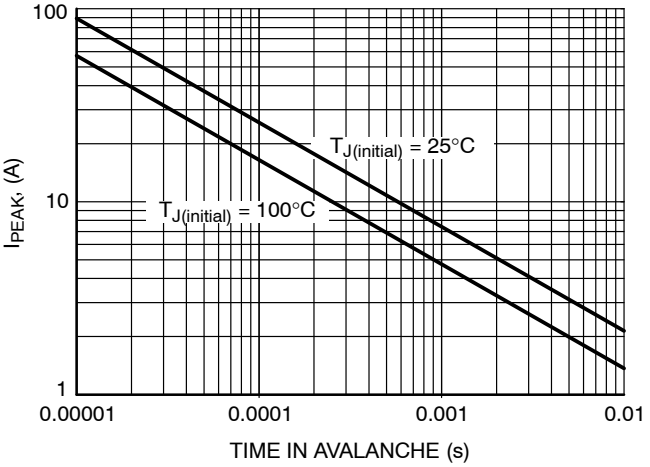



**Figure 12. Maximum Drain Current vs. Time in Avalanche**

## TYPICAL CHARACTERISTICS

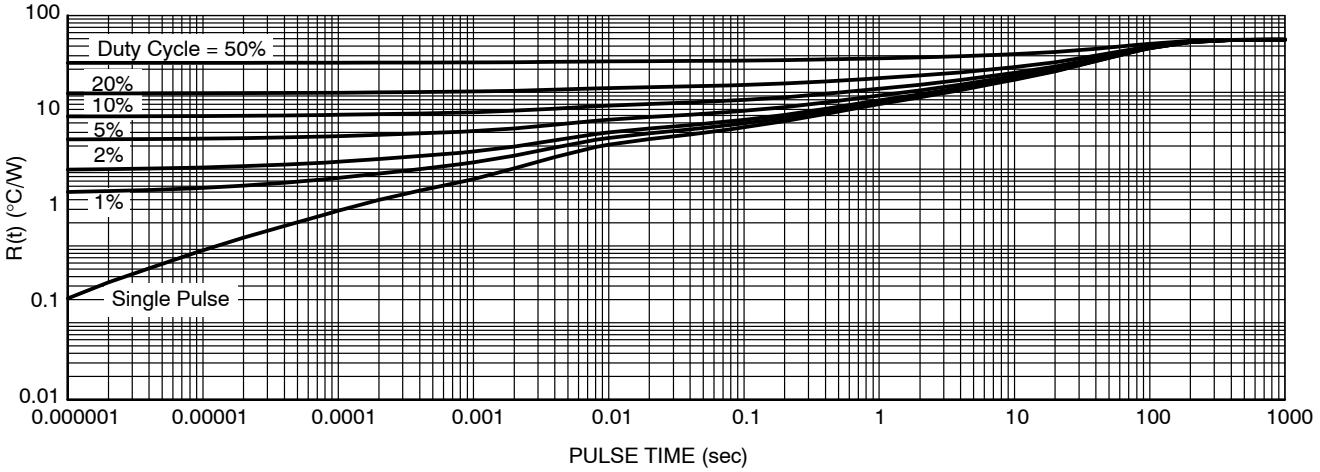



**Figure 13. Thermal Response**

### ORDERING INFORMATION

| Order Number | Package | Shipping† |
|---|---|---|
| NVD5C454NT4G | DPAK<br>(Pb−Free) | 2500 / Tape & Reel |

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

# MECHANICAL CASE OUTLINE
## PACKAGE DIMENSIONS

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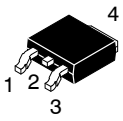
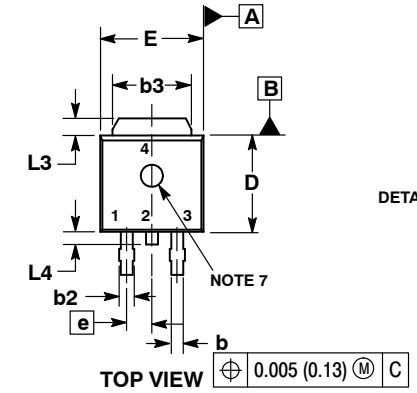
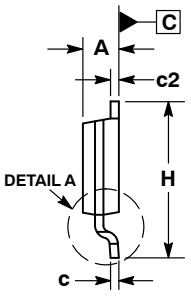


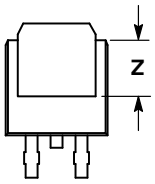

SCALE 1:1

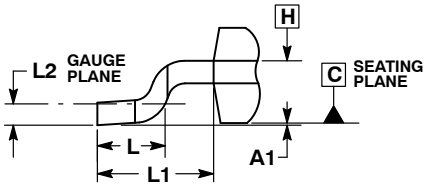
**DPAK (SINGLE GAUGE)**
CASE 369C
ISSUE F

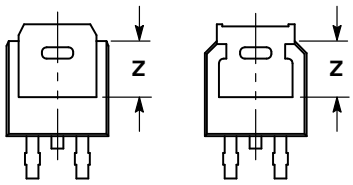
DATE 21 JUL 2015




NOTES:
1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
2. CONTROLLING DIMENSION: INCHES.
3. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSIONS b3, L3 and Z.
4. DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR BURRS. MOLD FLASH, PROTRUSIONS, OR GATE BURRS SHALL NOT EXCEED 0.006 INCHES PER SIDE.
5. DIMENSIONS D AND E ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
6. DATUMS A AND B ARE DETERMINED AT DATUM PLANE H.
7. OPTIONAL MOLD FEATURE.

| | INCHES | | MILLIMETERS | |
|---|---|---|---|---|
| DIM | MIN | MAX | MIN | MAX |
| A | 0.086 | 0.094 | 2.18 | 2.38 |
| A1 | 0.000 | 0.005 | 0.00 | 0.13 |
| b | 0.025 | 0.035 | 0.63 | 0.89 |
| b2 | 0.028 | 0.045 | 0.72 | 1.14 |
| b3 | 0.180 | 0.215 | 4.57 | 5.46 |
| c | 0.018 | 0.024 | 0.46 | 0.61 |
| c2 | 0.018 | 0.024 | 0.46 | 0.61 |
| D | 0.235 | 0.245 | 5.97 | 6.22 |
| E | 0.250 | 0.265 | 6.35 | 6.73 |
| e | 0.090 BSC | | 2.29 BSC | |
| H | 0.370 | 0.410 | 9.40 | 10.41 |
| L | 0.055 | 0.070 | 1.40 | 1.78 |
| L1 | 0.114 REF | | 2.90 REF | |
| L2 | 0.020 BSC | | 0.51 BSC | |
| L3 | 0.035 | 0.050 | 0.89 | 1.27 |
| L4 | --- | 0.040 | --- | 1.01 |
| Z | 0.155 | --- | 3.93 | --- |

STYLE 1:
PIN 1. BASE
2. COLLECTOR
3. EMITTER
4. COLLECTOR

STYLE 2:
PIN 1. GATE
2. DRAIN
3. SOURCE
4. DRAIN

STYLE 3:
PIN 1. ANODE
2. CATHODE
3. ANODE
4. CATHODE

STYLE 4:
PIN 1. CATHODE
2. ANODE
3. GATE
4. ANODE

STYLE 5:
PIN 1. GATE
2. ANODE
3. CATHODE
4. ANODE

STYLE 6:
PIN 1. MT1
2. MT2
3. GATE
4. MT2

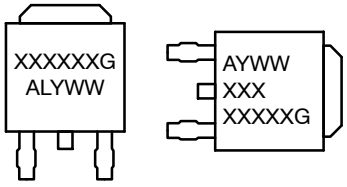
STYLE 7:
PIN 1. GATE
2. COLLECTOR
3. EMITTER
4. COLLECTOR

STYLE 8:
PIN 1. N/C
2. CATHODE
3. ANODE
4. CATHODE

STYLE 9:
PIN 1. ANODE
2. CATHODE
3. RESISTOR ADJUST
4. CATHODE

STYLE 10:
PIN 1. CATHODE
2. ANODE
3. CATHODE
4. ANODE

### GENERIC MARKING DIAGRAM*

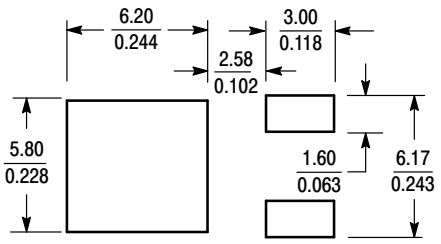



IC Discrete

XXXXXX = Device Code
A = Assembly Location
L = Wafer Lot
Y = Year
WW = Work Week
G = Pb−Free Package

*This information is generic. Please refer to device data sheet for actual part marking.

### SOLDERING FOOTPRINT*




SCALE 3:1 $\left(\frac{\text{mm}}{\text{inches}}\right)$

*For additional information on our Pb−Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

| | | |
|---|---|---|
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| DESCRIPTION: | DPAK (SINGLE GAUGE) | PAGE 1 OF 1 |

## PUBLICATION ORDERING INFORMATION

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Phone: 011 421 33 790 2910

**Europe, Middle East and Africa Technical Support:**
Phone: 00421 33 790 2910
For additional information, please contact your local Sales Representative

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